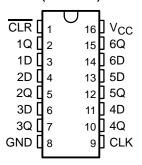
- EPIC™ (Enhanced-Performance Implanted CMOS) 2-μ Process
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   < 0.8 V at V<sub>CC</sub>, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   2 V at V<sub>CC</sub>, T<sub>A</sub> = 25°C
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), Ceramic Flat (W) Packages, Chip Carriers (FK), and (J) 300-mil DIPs

#### description

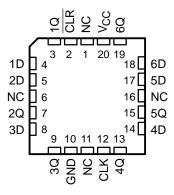
These hex D-type flip-flops are designed for 2.7-V to 5.5-V  $V_{CC}$  operation.

The 'LV174 are monolithic positive-edge-triggered flip-flops with a direct clear (CLR) input. Information at the data (D) inputs meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular

SN54LV174 . . . J OR W PACKAGE SN74LV174 . . . D, DB, OR PW PACKAGE (TOP VIEW)



SN54LV174 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

voltage level and is not directly related to the transition time of the positive-going edge of the clock pulse. When the clock (CLK) input is at either the high or low level, the D-input signal has no effect at the output.

The SN74LV174 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

The SN54LV174 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LV174 is characterized for operation from –40°C to 85°C.

#### **FUNCTION TABLE**

	INPUTS	ОИТРИТ	
CLR	CLK	D	Q
L	Х	Χ	L
Н	$\uparrow$	Н	Н
Н	$\uparrow$	L	L
Н	L	Χ	$Q_0$

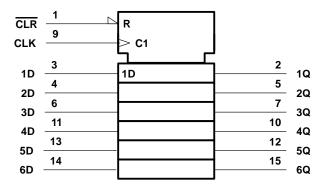


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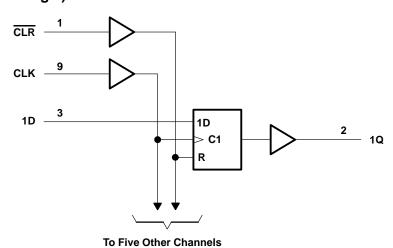


### logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, DB, J, PW, and W packages.

### logic diagram (positive logic)



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Output voltage range, VO (see Notes 1 and 2)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Maximum power dissipation at $T_A = 55^{\circ}$ C (in still air) (see Note 3	3): D package 1.3 W
	DB package 0.55 W
	PW package 0.5 W
Storage temperature range, T <sub>stg</sub>	65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. This value is limited to 7 V maximum.
- 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

### recommended operating conditions (see Note 4)

			SN54L	V174	SN74L	UNIT	
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		2.7	5.5	2.7	5.5	V
V	High lovel input voltege	V <sub>CC</sub> = 2.7 V to 3.6 V	2		2		V
VIH	High-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	3.15		3.15		V
V <sub>IL</sub> Low-	Low level input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8	0.8		V
	Low-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		1.65		1.65	]
VI	Input voltage		0	Vcc	0	VCC	V
۷o	Output voltage		0	VCC	0	VCC	V
la	High lovel output output	V <sub>CC</sub> = 2.7 V to 3.6 V	20	-6		-6	mA
ЮН	High-level output current	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	PO .	-12		-12	mA
la.	Low lovel output outpost	V <sub>CC</sub> = 2.7 V to 3.6 V		6		6	A
IOL	Low-level output current $V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$			12		12	mA
Δt/Δν	Input transition rise or fall rate		0	100	0	100	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	,, <sub>+</sub>	SN54LV174	SN74LV174	UNIT
PARAMETER	TEST CONDITIONS	v <sub>cc</sub> †	MIN TYP MAX	MIN TYP MAX	UNII
	I <sub>OH</sub> = -100 μA	MIN to MAX	V <sub>CC</sub> - 0.2	V <sub>CC</sub> - 0.2	
Voн	I <sub>OH</sub> = -6 mA	3 V	2.4	2.4	V
	I <sub>OH</sub> = -12 mA	4.5	3.6	3.6	
	I <sub>OL</sub> = 100 μA	MIN to MAX	0.2	0.2	
V <sub>OL</sub>	I <sub>OL</sub> = 6 mA	3 V	0.4	0.4	V
	I <sub>OL</sub> = 12 mA	4.5 V	0.55	0.55	
1.	V <sub>I</sub> = V <sub>CC</sub> or GND	3.6 V	±1	±1	μΑ
t <sub>1</sub>	Al = ACC OLGIAD	5.5 V	Ú ±1	±1	μΑ
laa	Vi – Voe er CND	3.6 V	20	20	
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	20	μΑ
ΔI <sub>CC</sub>	One input at V <sub>CC</sub> – 0.6 V, Other inputs at V <sub>CC</sub> or GND	3 V to 3.6 V	500	500	μА
C.	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V	2.5	2.5	pF
Ci	AL = ACC OL GIAD	5 V	3	3	þΓ

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

							SN54LV174						
				= 5 V 5 V	V <sub>CC</sub> =		V <sub>CC</sub> =	2.7 V	UNIT				
			MIN	MAX	MIN	MAX	MIN	MAX					
f <sub>clock</sub>	Clock frequency		0	40	0	30	0	24	MHz				
	Pulse duration	CLR low	12		18		22						
t <sub>W</sub>	Fulse duration	CLK high or low	12	-01	18	~	22		ns				
	Oatom Care before OLIC	Data	10	o Pro	12	Sho	14						
t <sub>su</sub>	Setup time before CLK↑	CLR inactive	3	, 66	3	, 6	3		ns				
th	Hold time, data after CLK↑		3		3		3		ns				

## timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

					SN74L	.V174				
				V <sub>CC</sub> = 5 V ± 0.5 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		2.7 V	UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX		
fclock	Clock frequency		0	40	0	30	0	24	MHz	
	Pulse duration	CLR low	12		18		22		ns	
t <sub>w</sub>	Pulse duration	CLK high or low	12		18		22		115	
	Satura tima a hafarra CLIVA	Data	10		12		14		no	
t <sub>su</sub>	Setup time before CLK↑		3		3		3		ns	
th	Hold time, data after CLK↑		3		3		3		ns	

# switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER				SN54LV174							
	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> :	V <sub>CC</sub> = 5 V ± 0.5 V V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 2.7 V		UNIT			
	(1011 (1011)	MIN	TYP	MAX	MIN	TYP	MAX	_ MIN	MAX		
f <sub>max</sub>			40	90	O.	30	80	-0 <sup>1</sup>	24		MHz
<sup>t</sup> pd	CLR	0		9	18	JIL	12	23	Alle	28	ns
	CLK	Q		8	20	,	13	29		36	115

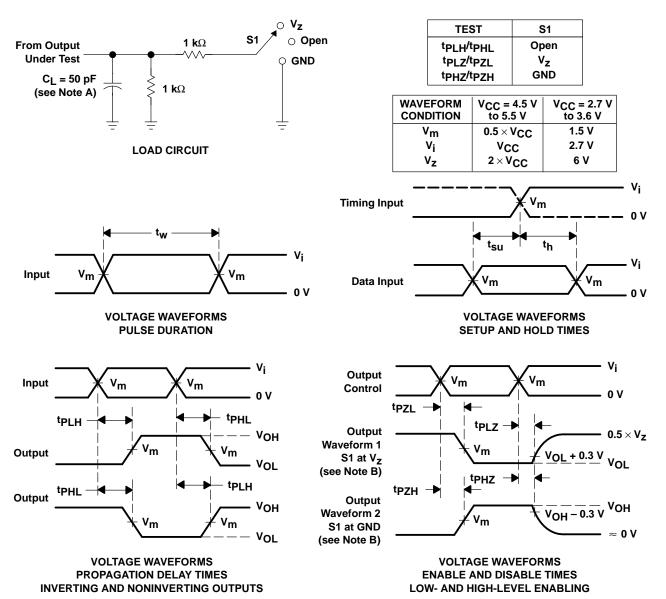
# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

						SN74L	.V174				
PARAMETER	FROM (INPUT)	TO (OUTPUT)	VCC:	= 5 V ± 0	).5 V	V <sub>CC</sub> =	3.3 V $\pm$	0.3 V	V <sub>CC</sub> =	2.7 V	UNIT
	(1141 01)		MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX	
f <sub>max</sub>			40	90		30	80		24		MHz
<sup>t</sup> pd	CLR	0		9	18		12	23		28	ns
	CLK	Q		8	20		13	29		36	115

### operating characteristics, T<sub>A</sub> = 25°C

PARAMETER		TEST CONDITIONS	VCC	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per flip-flop	$C_1 = 50 \text{ pF},  f = 10 \text{ MHz}$	3.3 V	24	nE
		CL = 50 pr, 1 = 10 MH2	5 V	52	pF

#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f \leq 2.5 \ ns$ .
  - D. The outputs are measured one at a time with one transition per measurement.
  - E. tpLz and tpHz are the same as tdis.
  - F. tpzL and tpzH are the same as ten.
  - G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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